



Keep it Cheap: Multiple Faults Attacks in Practice

Karim Abdellatif and Olivier Hériveaux

Karim.abdellatif,olivier.heriveaux@ledger.fr



- Building homemade tools for injecting faults
- Considering low cost components
- Validation on IoT chips



Fault Injection in Donjon



Clock Glitch



Power Glitch



Electromagnetic



Laser





- ❖ Why Multiple Fault Attacks?
- ❖ Low cost synchronization
- ❖ Power glitch setup
- ❖ EM setup
- ❖ Conclusion



- **An IoT chip has three different configuration modes**
 - **A**: No security feature is activated
 - **B**: Bootloader is enabled, but commands used to read and write memory are disabled
 - **C**: All the security features for IP protection are enabled
- **The goal is to convert the configuration from C to A to dump the firmware (memory)**



Algorithm 1: Attack sequence of C configuration

while *True* **do**

 Initialize-Fault(parameters);

 uart.transmit(X, trigger=1);

if (*uart.receive=ACCEPT*) **then**

 Go to **B configuration attack**;

Algorithm 2: Attack sequence of B configuration

Initialize-Fault(parameters);

Read Memory Content (trigger=1, address, number of bytes);

if (*uart.receive=ACCEPT*) **then**

 Data=uart.receive(number of bytes);

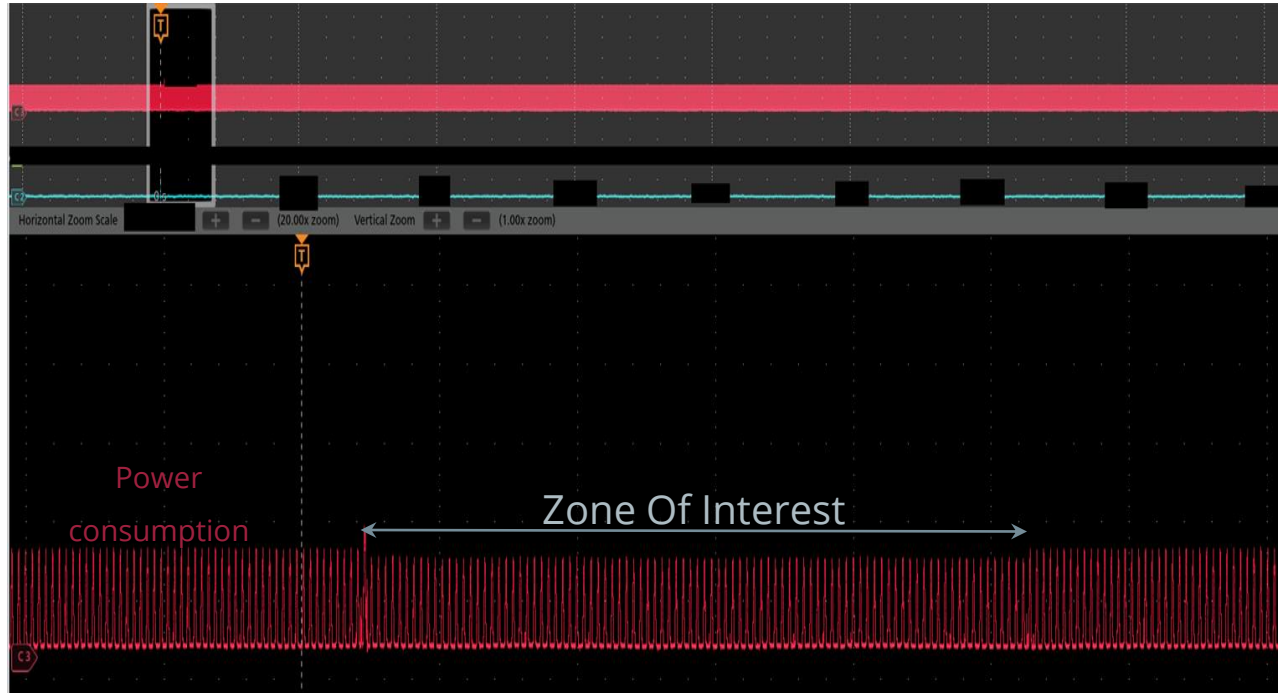
else

 Data=None;

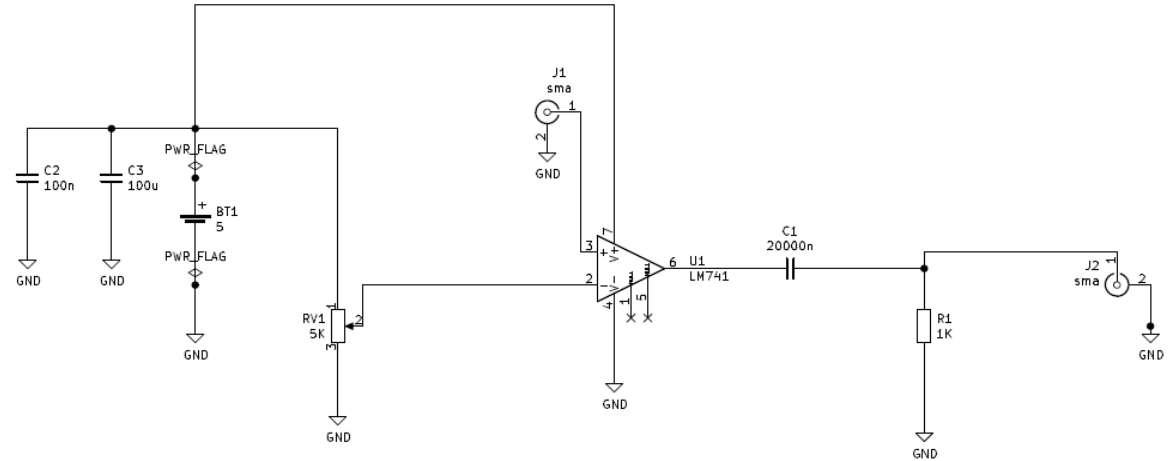
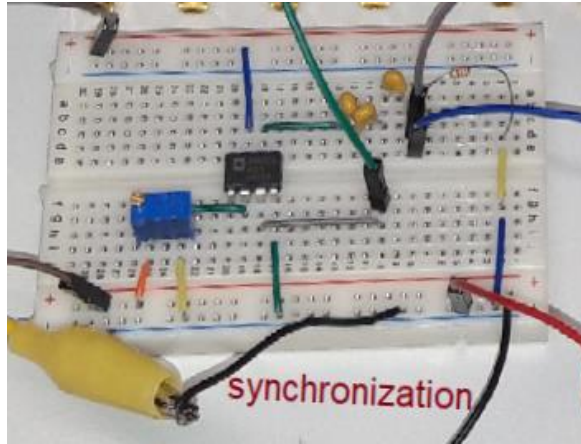
To dump the memory: **Two fault attacks**
(or more) must be chained!



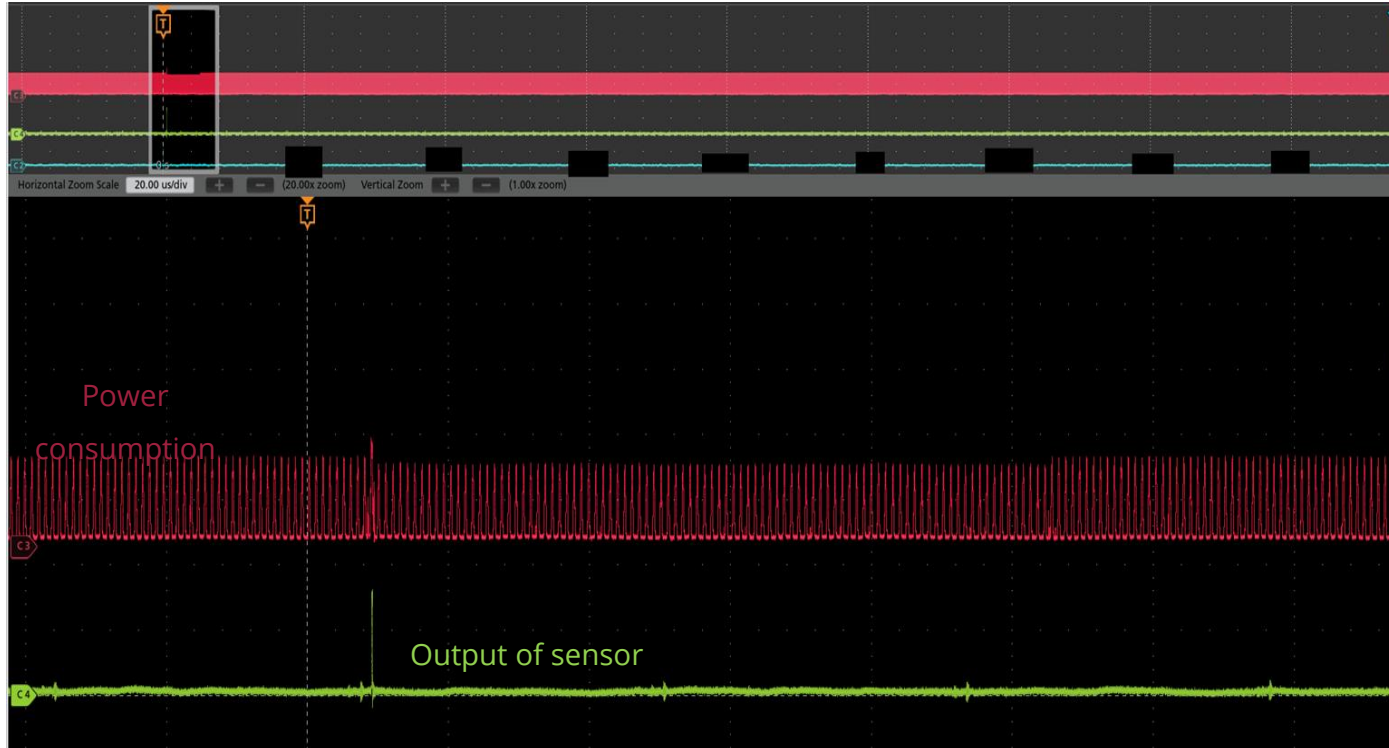
Example: Configuration B



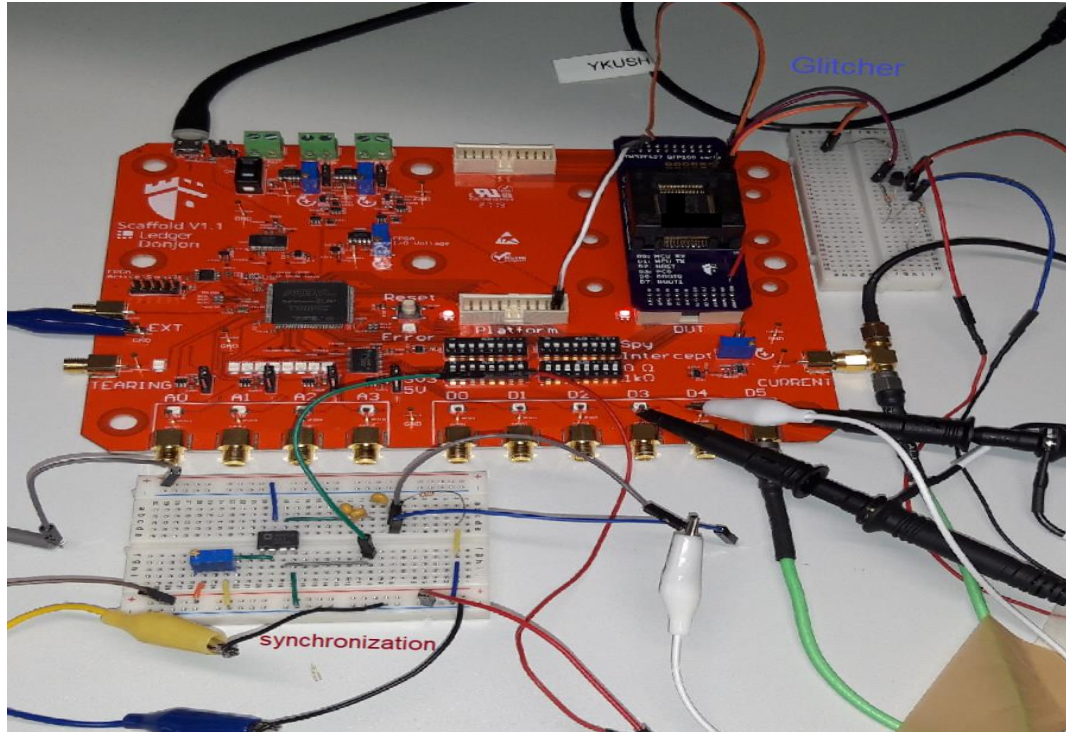
Analog sensor



Synchronization

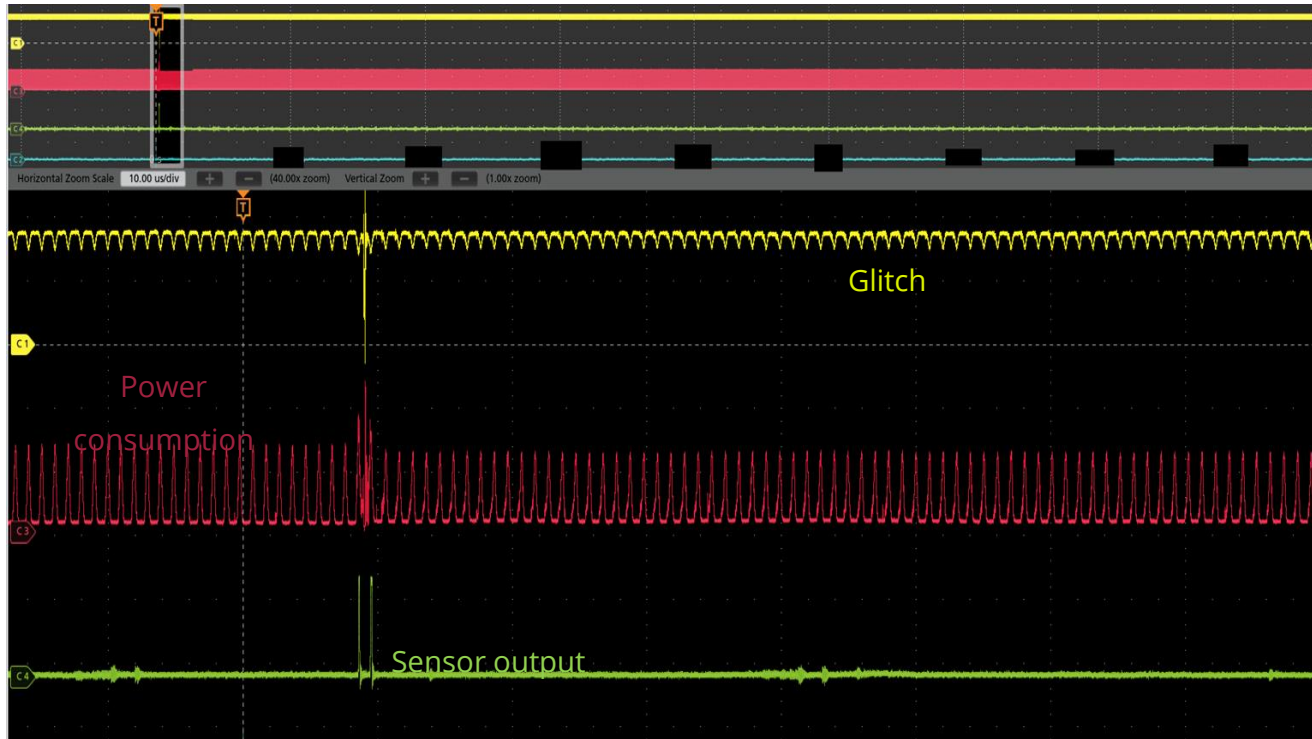


Setup

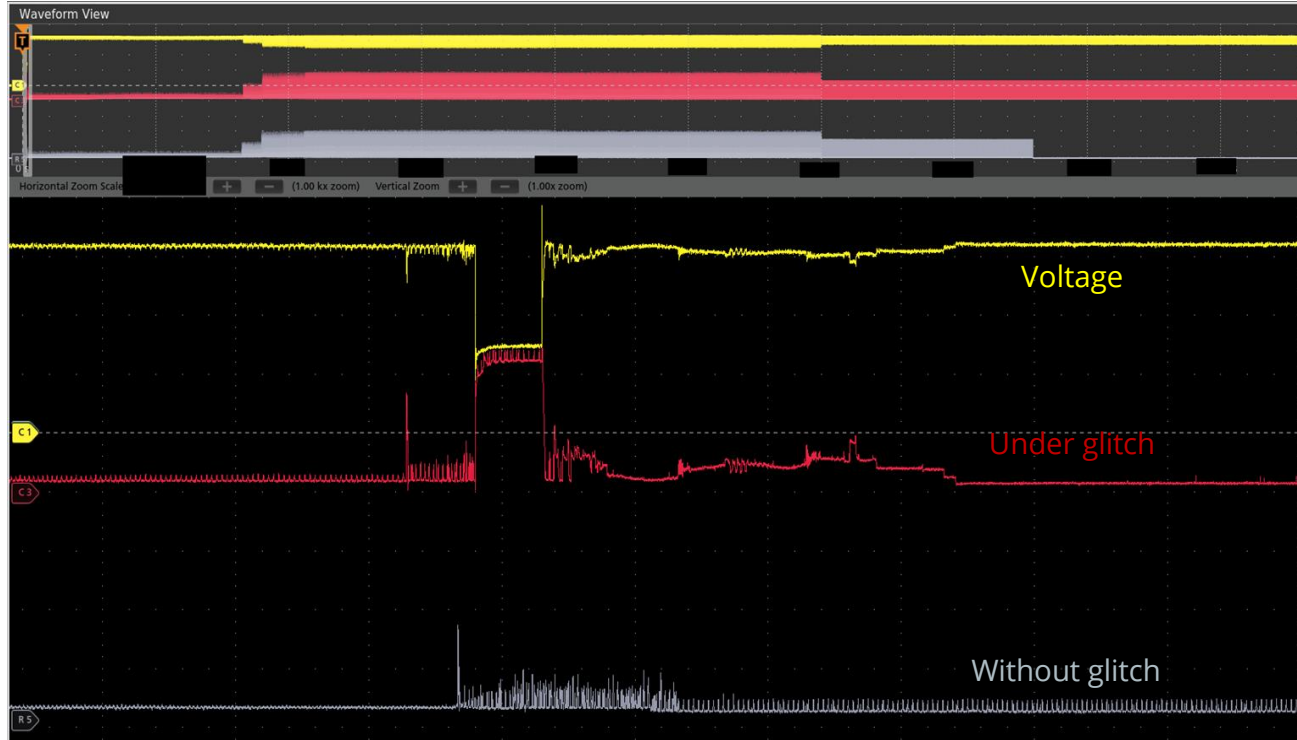


Scaffold: <https://github.com/Ledger-Donjon/scaffold>

B configuration (Successful attack)



C configuration (Successful attack)



Low Cost EM Setup: SiliconToaster [FDTC-2020]



ChipSHOUTER, \$3300 USD
(NewAe)

ChipSHOUTER: <http://store.newae.com/chipshouter-kit/>

Setups from Academia



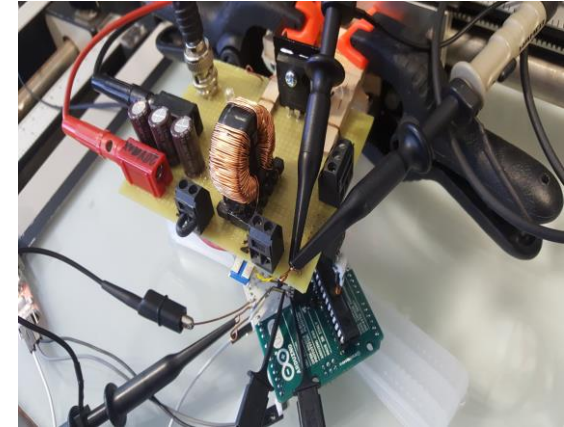
Ordas et al. (FDTC 2015)

- **Commercial** pulse generator



Cui et al. (USENIX 2017)

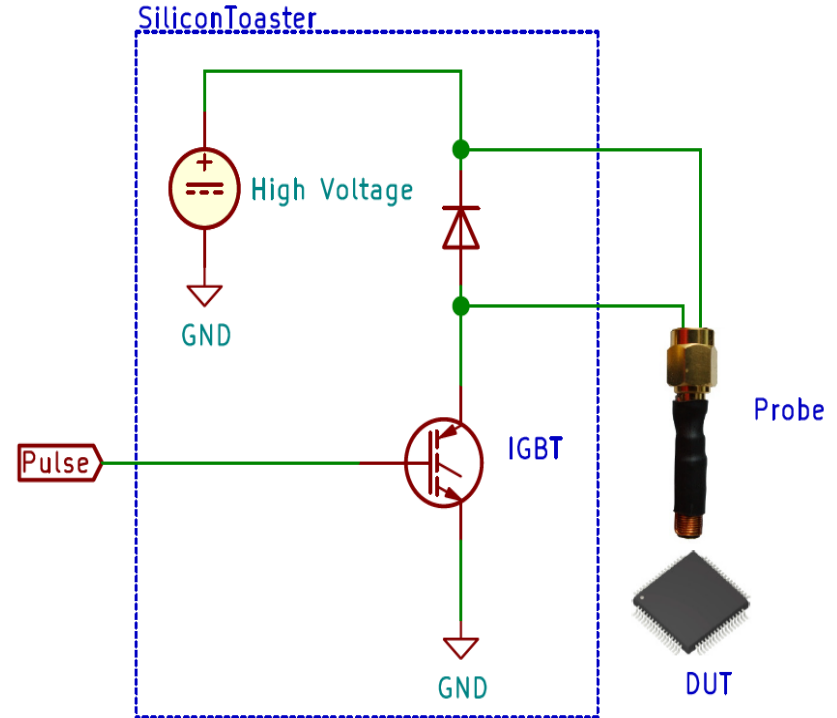
- Hand-made pulse generator with **fixed voltage**
- **External power** supply to feed the pulse generator



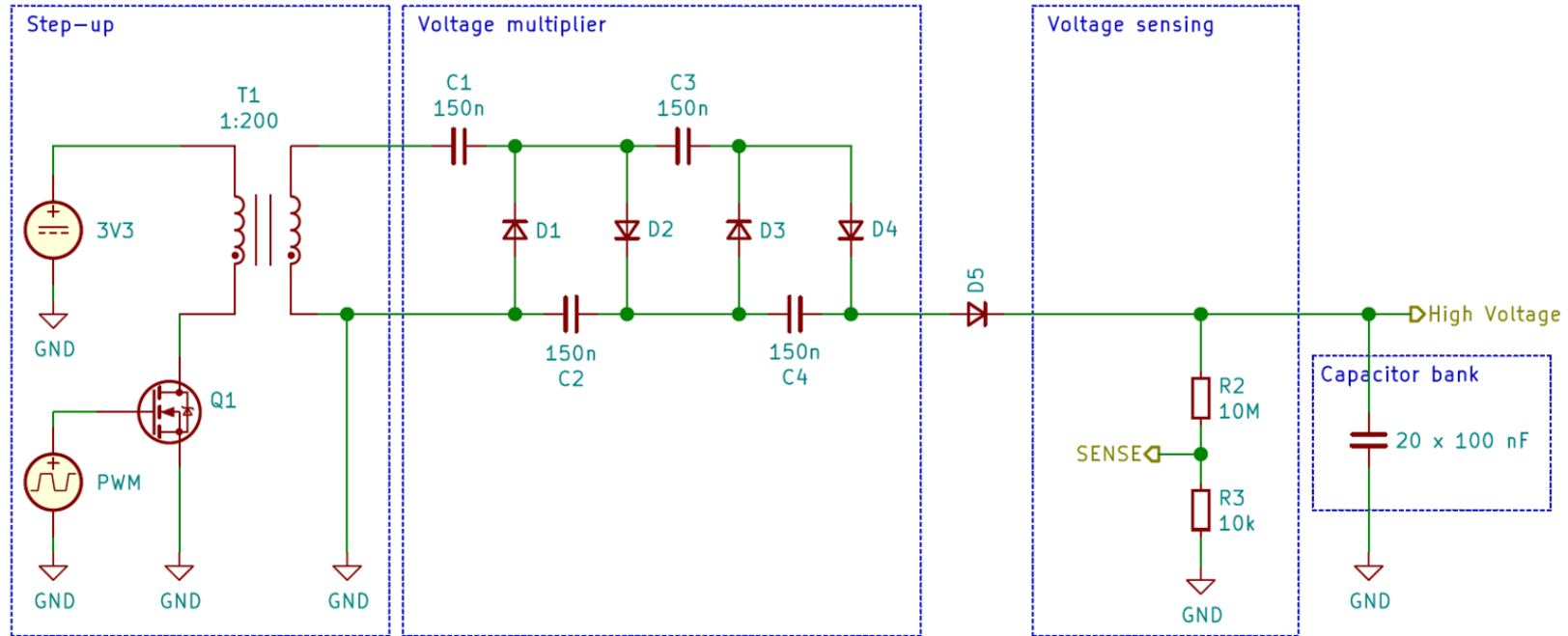
Balasch et al. (DCIS 2017)



- Programmable high voltage generation up to 1.2KV
- High voltage switching circuit
- Probe fabrication



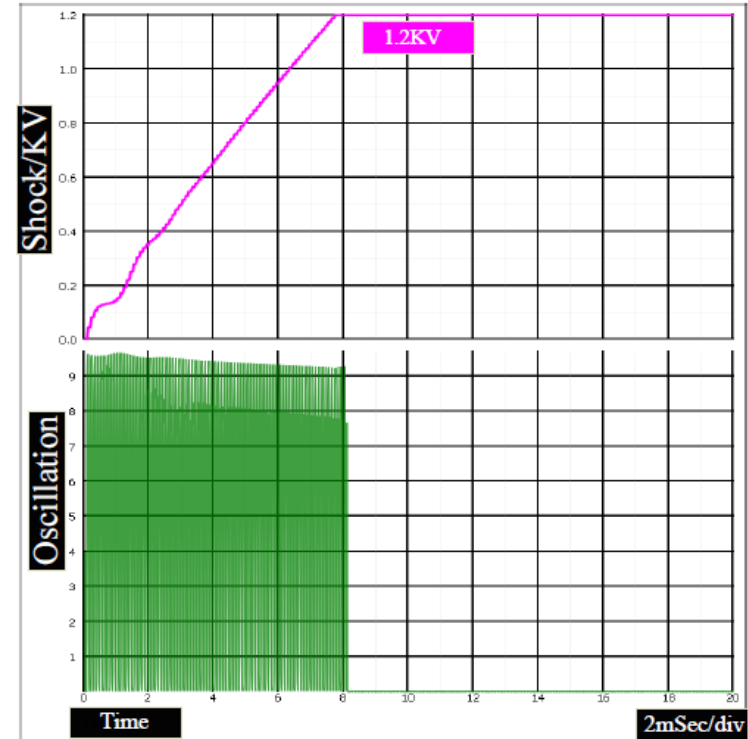
High Voltage Generator



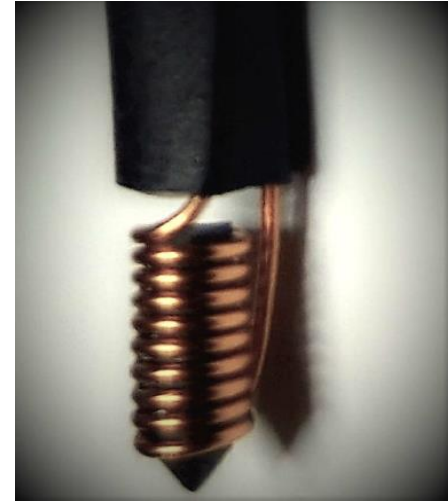
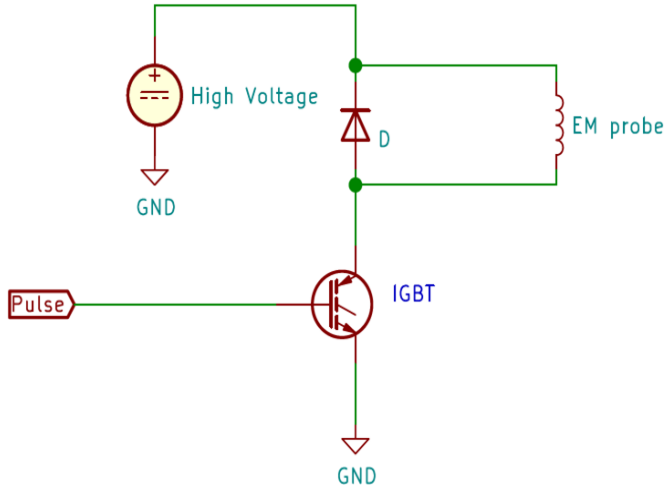
Programmable Voltage



- The generated high voltage depends on several parameters such as:
 - Number of pulses
 - Frequency of the input pulses
 - Pulse width
- With 8ms of pulses and frequency of 10KHZ, the output voltage is 1.2kV



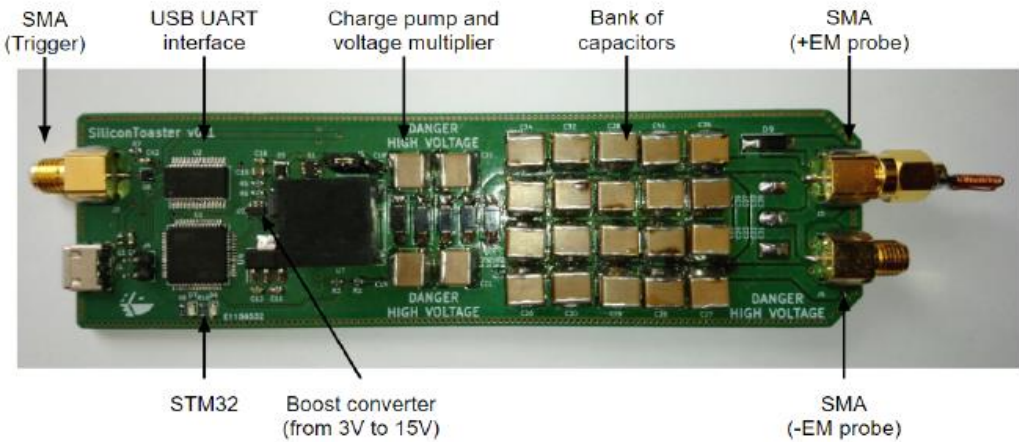
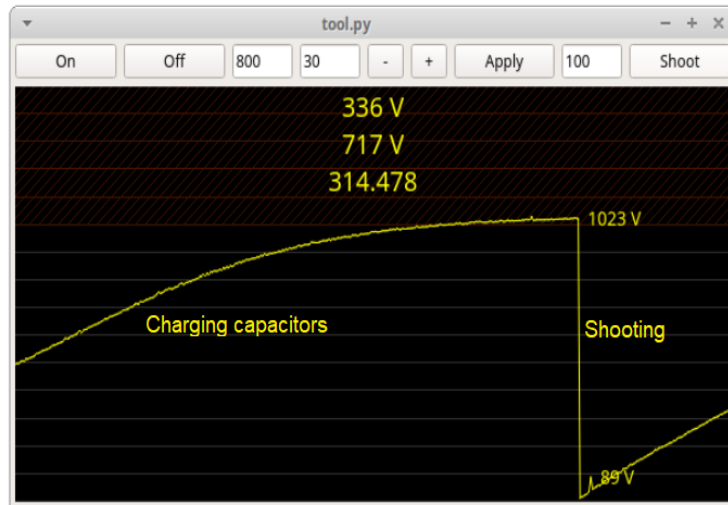
High Voltage Switching circuit + Probe fabrication



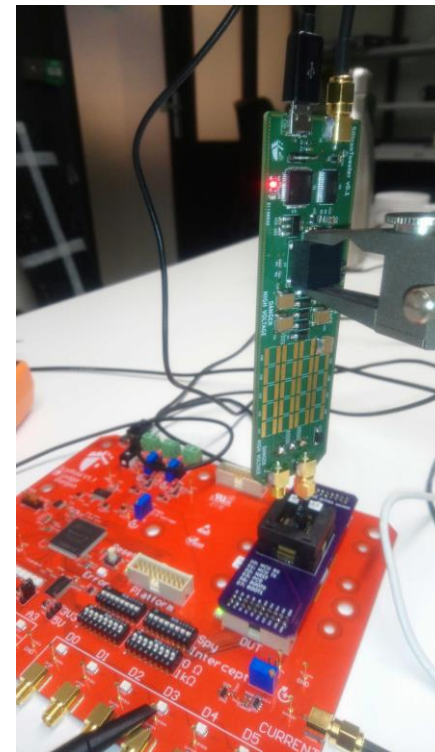
- IGBT: maximum ratings are 1.2kV collector-emitter voltage, 40A pulsed current and 20V gate-to-emitter voltage

- Fabricated from a flat coil of 6.6 mm diameter with 9 turns

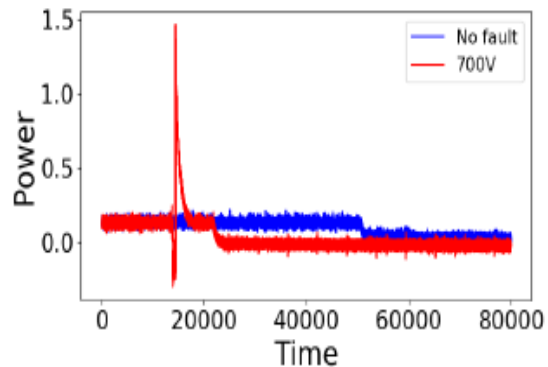
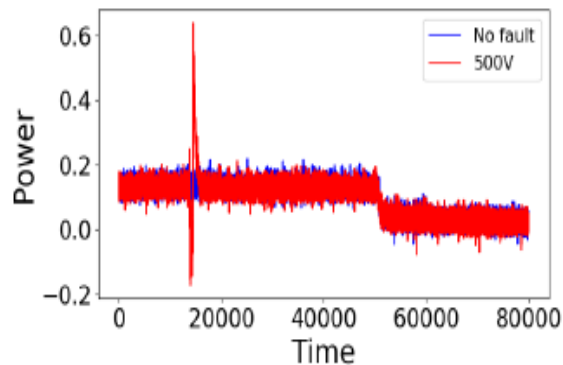
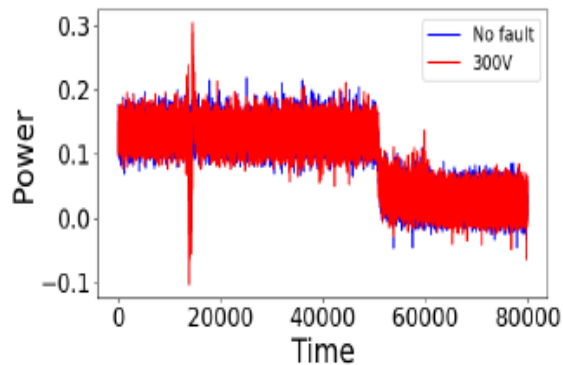
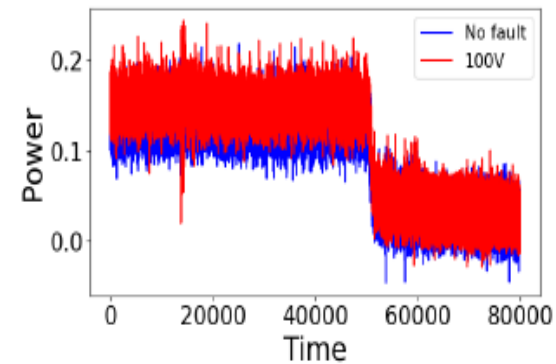
Final Model + GUI



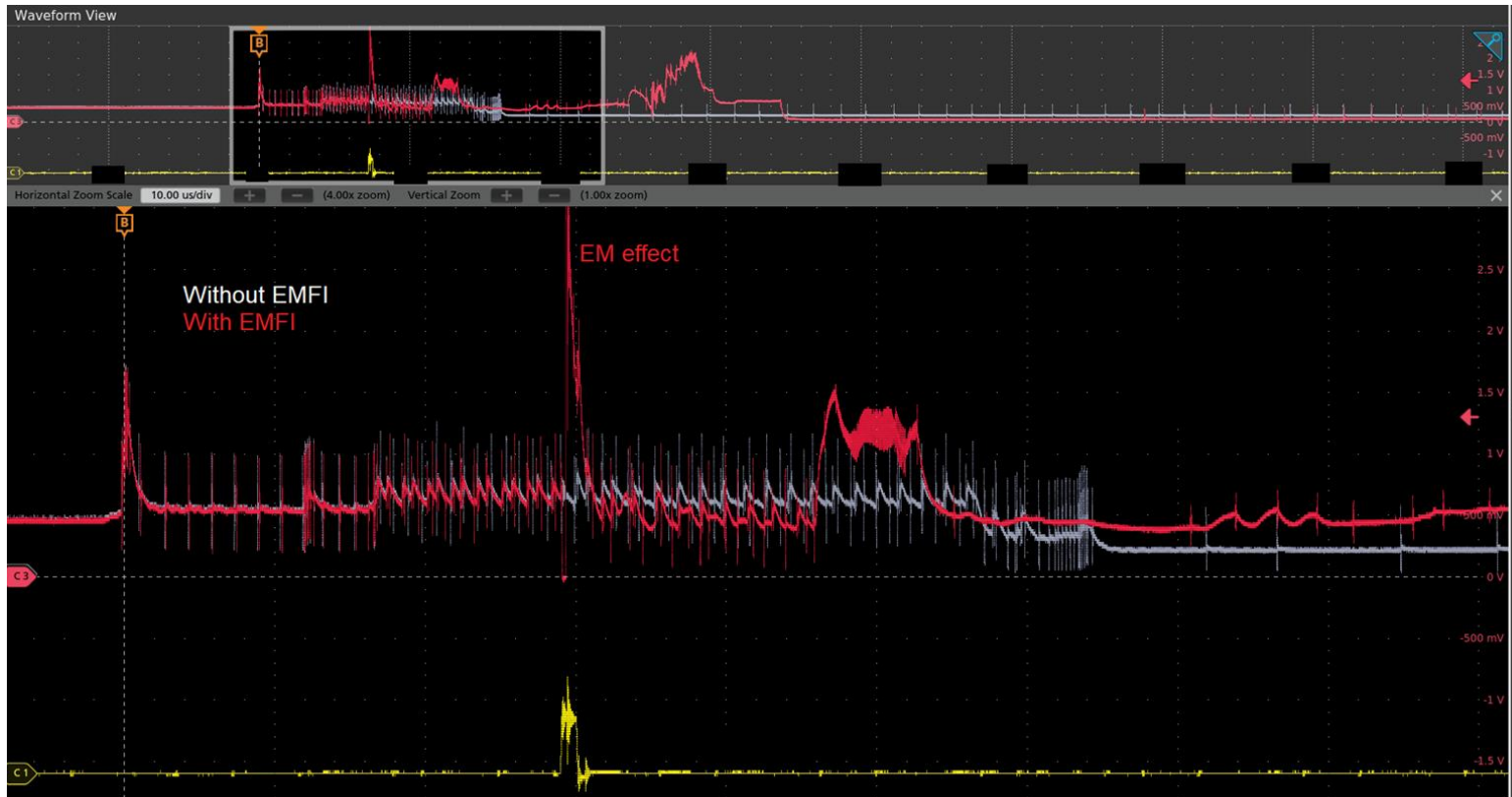
- The DUT was placed in a custom board socket
- **SiliconToaster** is used for injecting EM pulses to bypass the security configuration modes
- **Scaffold** board is also used to communicate with the DUT



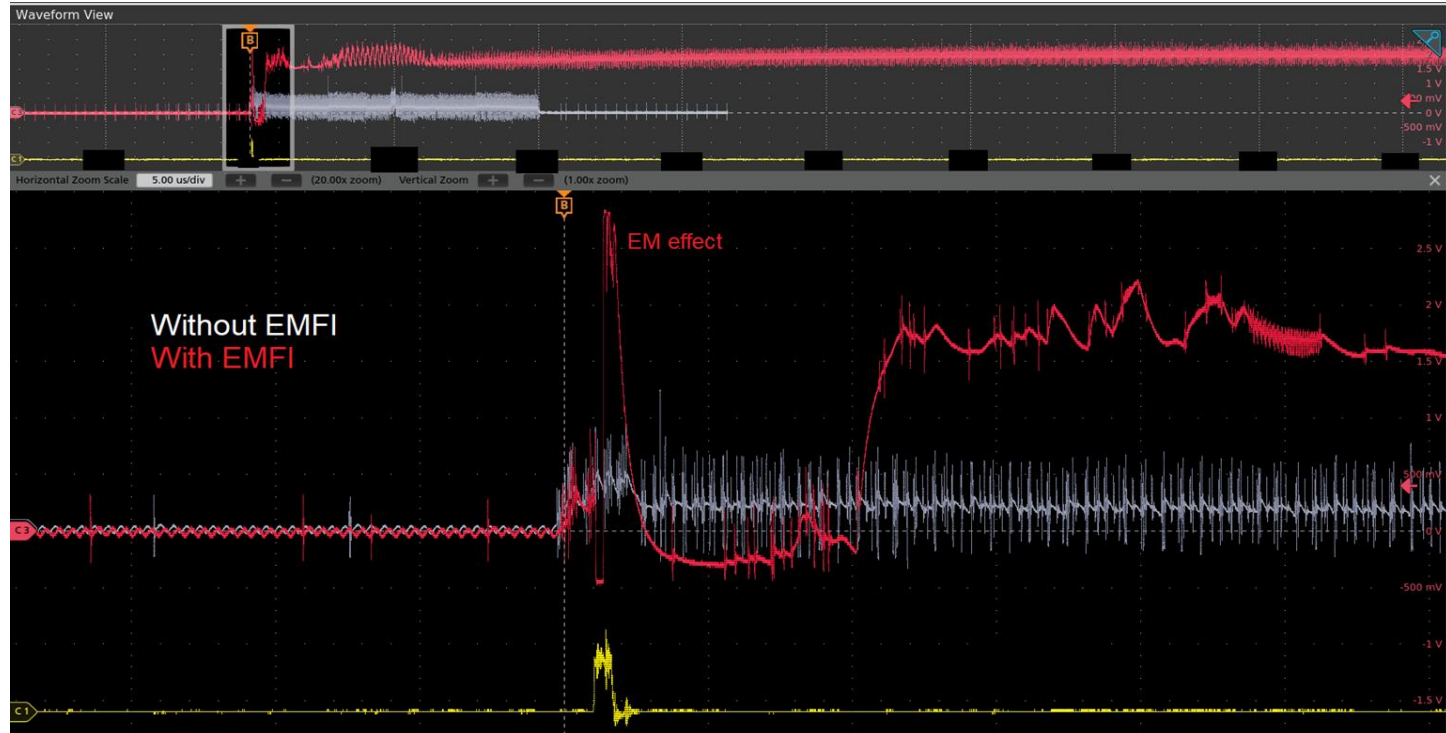
Programmable EM Pulse



C Configuration Attack: 400V + Success= 60%



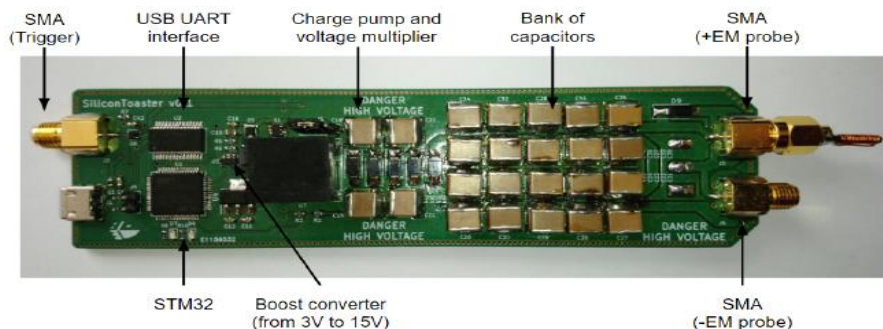
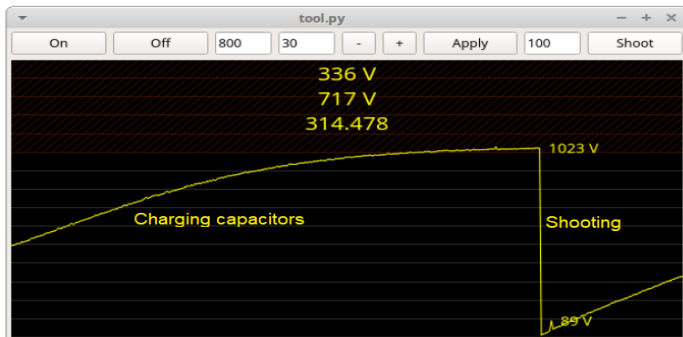
B configuration Attack: 400V + Success= 30%



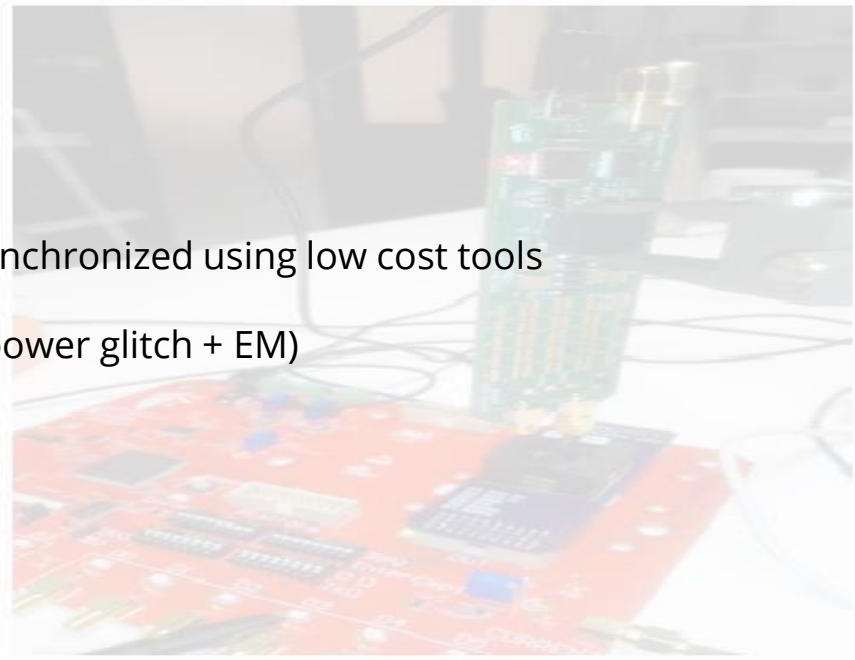
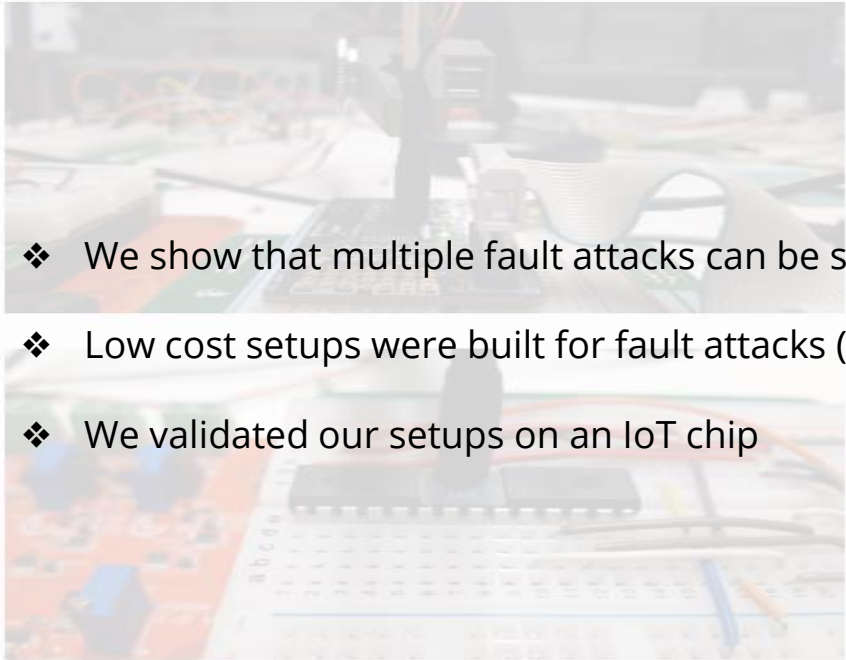
Comparison with previous work



Design	EM voltage	Power supply	Visibility	Polarity
SiliconToaster	Programmable	USB-powered	GUI	Two SMA
USENIX 2017 + DCIS 2017	Fixed	External power supply	No	Another probe needed



- ❖ We show that multiple fault attacks can be synchronized using low cost tools
- ❖ Low cost setups were built for fault attacks (power glitch + EM)
- ❖ We validated our setups on an IoT chip





Questions?